

ANALYSIS OF "NON-IDEAL" SAMPLES BY EDXRF FOR CR, HG, PB, BR AND CD IN A VARIETY OF CONSUMER ELECTRONIC COMPONENTS

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The application of measuring a variety of shapes, sizes, thicknesses and material types for the purpose of screening consumer electronics and electrical apparatuses to ensure the restriction of certain hazardous elements and compounds (Cr6+, Hg, Pb, PBDE, PBB and Cd) poses a challenge to screening methods. The XRF technique has some unique advantages to offer in the need for this screening process.

The advantages and disadvantages of the technique will be explained as well as some of the ways that XRF can be adapted to deal with “non-ideal” samples.